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PTO/SB/08A (08-00)

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**Substitute for form 1449A/PTO
(modified)
INFORMATION DISCLOSURE
STATEMENT BY APPLICANT
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Sheet

1

of

3

Complete if known

Application Number	Not yet assigned
Filing Date	Concurrently Herewith
First Named Inventor	Horst Haussecker
Group Art Unit	Not yet assigned
Examiner Name	Not yet assigned
Attorney Docket	42P14242X

U.S. PATENT DOCUMENTS

Examiner Initials	Cite No. ¹	U.S. Patent Document Number	Kind Code ² (if known)	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines Where Relevant Passages or Figures Appear
BL		5,472,881		Beebe, et al.	12/05/1995	
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		6,157,921		Barnhill	12/05/2000	
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OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS

Examiner Initials	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
BL		United States Patent Application Publication, Publication No. US 2001/0052257, Magerle, Publication Date December 20, 2001.	

Examiner Signature	<i>Beebe</i>	Date Considered	08/29/05
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¹Unique citation designation number. ²See attached Kinds of U.S. Patent Documents. ³Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵Kind of document by the appropriate symbols as indicated on the document under WIPO Standard St.16 if possible. ⁶Applicant is to place a check mark here if English language Translation is attached.

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BL		ANDO, et al., "A High-Speed Atomic Force Microscope for Studying Biological Macromolecules," <i>PNAS</i> , Vol. 98, No. 22, pp. 12468-12472, October 2001.	
		CLAUSS, et al., "Atomic Resolution STM Imaging of a Twisted Single-Wall Carbon Nanotube," <i>Physical Review B</i> , Volume 58, Number 8, pp. 4266-4269, August 1998.	
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Examiner Signature	<i>Bruce</i>	Date Considered	06/29/05
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BL		KOBAYASHI, et al., "Imaging of Fullerene Molecules on Si(111)-7 7 Surface with NC-AFM," <i>Applied Surface Science</i> , 157, pp. 228-232, 2000.		
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		THUNDAT, et al., "Atomic Force Microscopy of DNA on Mice and Chemically Modified Mica," <i>Scanning Microsc.</i> 6:911-8, 1992.		
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